

<b>Notice of References Cited</b>	Application/Control No. 10/046,188	Applicant(s)/Patent Under Reexamination LICH, YUVAL	
	Examiner Anthony Weier	Art Unit 1761	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5852966	12-1998	Hursh	---
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N	JP 08150080	06-1996	Japan	---	---
	O					
	P					
	Q					
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